Uncertainty source	Type	Effect on simulated signal yield
Tracking efficiency	Normalization	4.6–4.8%
Ditrack isolation efficiency	Normalization	2%
Ditrack isolation efficiency extrapolation	Shape	1–6%
Muon efficiency	Normalization	1%
Muon energy scale	Shape	$< 0.3\%$
Electron efficiency	Normalization	2–3%
Electron energy scale	Shape	$< 0.3\%$
Integrated luminosity	Normalization	2.3–2.5%
Inelastic cross section	Shape	0.5–1.5%
Production cross section	Normalization	0.4–3.9%
Choice of PDF and α_s	Normalization	1.6–3.2%
Limited size of simulated samples	Shape	Bin-dependent